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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

| | |
|--------------------------------|---|
| Product Status | Obsolete |
| Number of LABs/CLBs | 196 |
| Number of Logic Elements/Cells | 784 |
| Total RAM Bits | - |
| Number of I/O | 148 |
| Number of Gates | 10000 |
| Voltage - Supply | 4.75V ~ 5.25V |
| Mounting Type | Surface Mount |
| Operating Temperature | 0°C ~ 85°C (TJ) |
| Package / Case | 208-BFQFP |
| Supplier Device Package | 208-PQFP (28x28) |
| Purchase URL | https://www.e-xfl.com/product-detail/xilinx/xc5206-5pq208c |

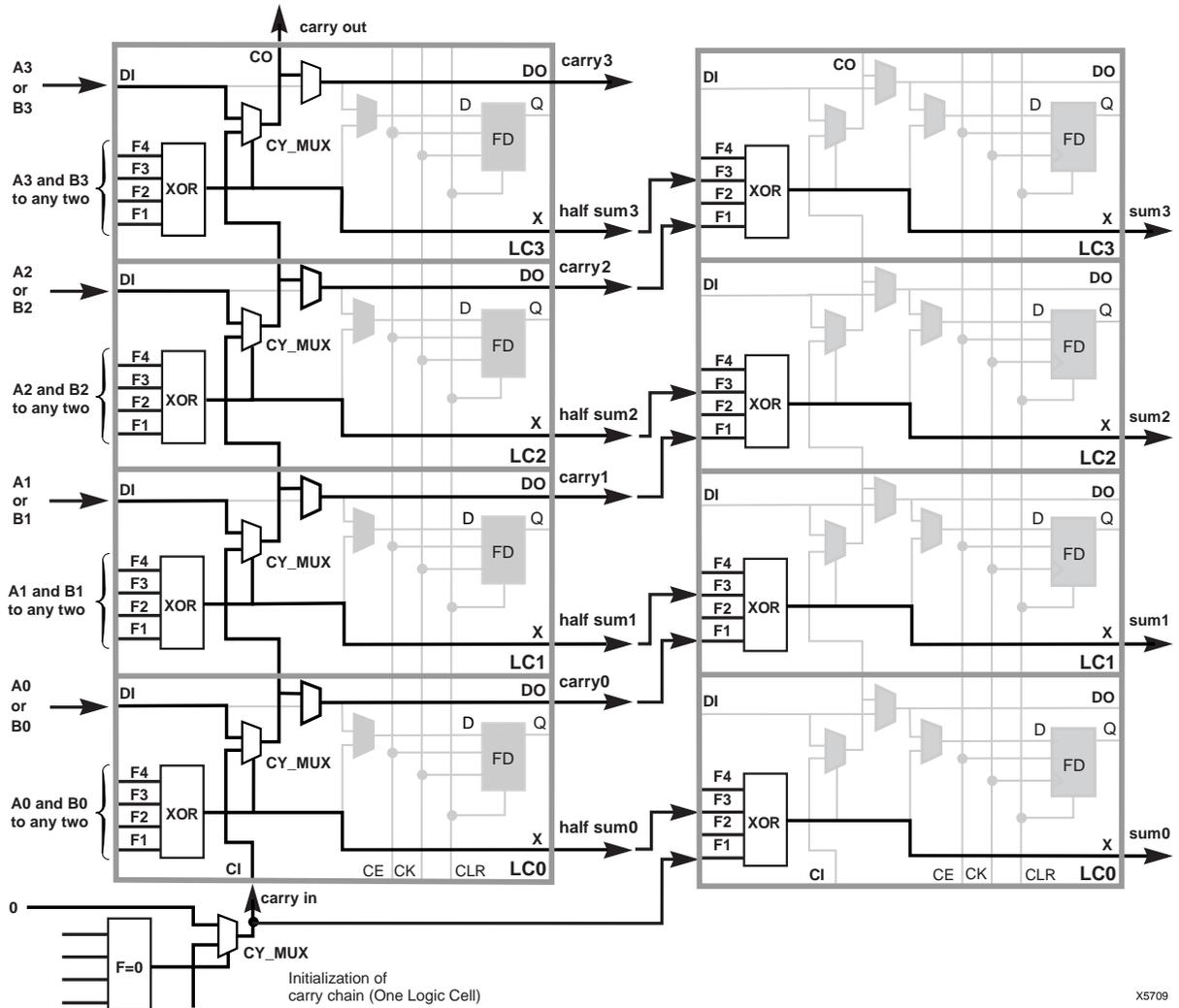


Figure 6: XC5200 CY_MUX Used for Adder Carry Propagate

Carry Function

The XC5200 family supports a carry-logic feature that enhances the performance of arithmetic functions such as counters, adders, etc. A carry multiplexer (CY_MUX) symbol is used to indicate the XC5200 carry logic. This symbol represents the dedicated 2:1 multiplexer in each LC that performs the one-bit high-speed carry propagate per logic cell (four bits per CLB).

While the carry propagate is performed inside the LC, an adjacent LC must be used to complete the arithmetic function. Figure 6 represents an example of an adder function. The carry propagate is performed on the CLB shown,

which also generates the half-sum for the four-bit adder. An adjacent CLB is responsible for XORing the half-sum with the corresponding carry-out. Thus an adder or counter requires two LCs per bit. Notice that the carry chain requires an initialization stage, which the XC5200 family accomplishes using the carry initialize (CY_INIT) macro and one additional LC. The carry chain can propagate vertically up a column of CLBs.

The XC5200 library contains a set of Relationally-Placed Macros (RPMs) and arithmetic functions designed to take advantage of the dedicated carry logic. Using and modifying these macros makes it much easier to implement cus-

can also be independently disabled for any flip-flop. CLR is active High. It is not invertible within the CLB.

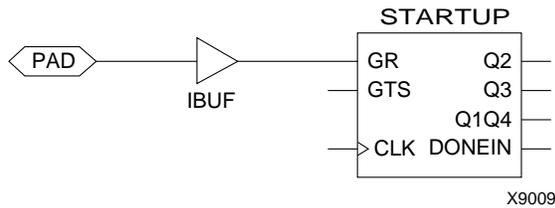


Figure 8: Schematic Symbols for Global Reset

Global Reset

A separate Global Reset line clears each storage element during power-up, reconfiguration, or when a dedicated Reset net is driven active. This global net (GR) does not compete with other routing resources; it uses a dedicated distribution network.

GR can be driven from any user-programmable pin as a global reset input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GR pin of the STARTUP symbol. (See Figure 9.) A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global Reset signal. Alternatively, GR can be driven from any internal node.

Using FPGA Flip-Flops and Latches

The abundance of flip-flops in the XC5200 Series invites pipelined designs. This is a powerful way of increasing performance by breaking the function into smaller subfunctions and executing them in parallel, passing on the results through pipeline flip-flops. This method should be seriously considered wherever throughput is more important than latency.

To include a CLB flip-flop, place the appropriate library symbol. For example, FDCE is a D-type flip-flop with clock enable and asynchronous clear. The corresponding latch symbol is called LDCE.

In XC5200-Series devices, the flip-flops can be used as registers or shift registers without blocking the function generators from performing a different, perhaps unrelated task. This ability increases the functional capacity of the devices.

The CLB setup time is specified between the function generator inputs and the clock input CK. Therefore, the specified CLB flip-flop setup time includes the delay through the function generator.

Three-State Buffers

The XC5200 family has four dedicated Three-State Buffers (TBUFs, or BUFTs in the schematic library) per CLB (see Figure 9). The four buffers are individually configurable through four configuration bits to operate as simple non-inverting buffers or in 3-state mode. When in 3-state mode the CLB output enable (TS) control signal drives the enable to all four buffers. Each TBUF can drive up to two horizontal and/or two vertical Longlines. These 3-state buffers can be used to implement multiplexed or bidirectional buses on the horizontal or vertical longlines, saving logic resources.

The 3-state buffer enable is an active-High 3-state (i.e. an active-Low enable), as shown in Table 4.

Table 4: Three-State Buffer Functionality

| IN | T | OUT |
|----|---|-----|
| X | 1 | Z |
| IN | 0 | IN |

Another 3-state buffer with similar access is located near each I/O block along the right and left edges of the array.

The longlines driven by the 3-state buffers have a weak keeper at each end. This circuit prevents undefined floating levels. However, it is overridden by any driver. To ensure the longline goes high when no buffers are on, add an additional BUFT to drive the output High during all of the previously undefined states.

Figure 10 shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.

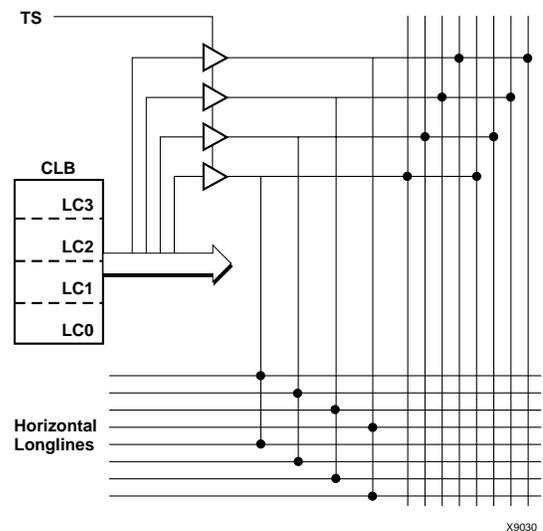
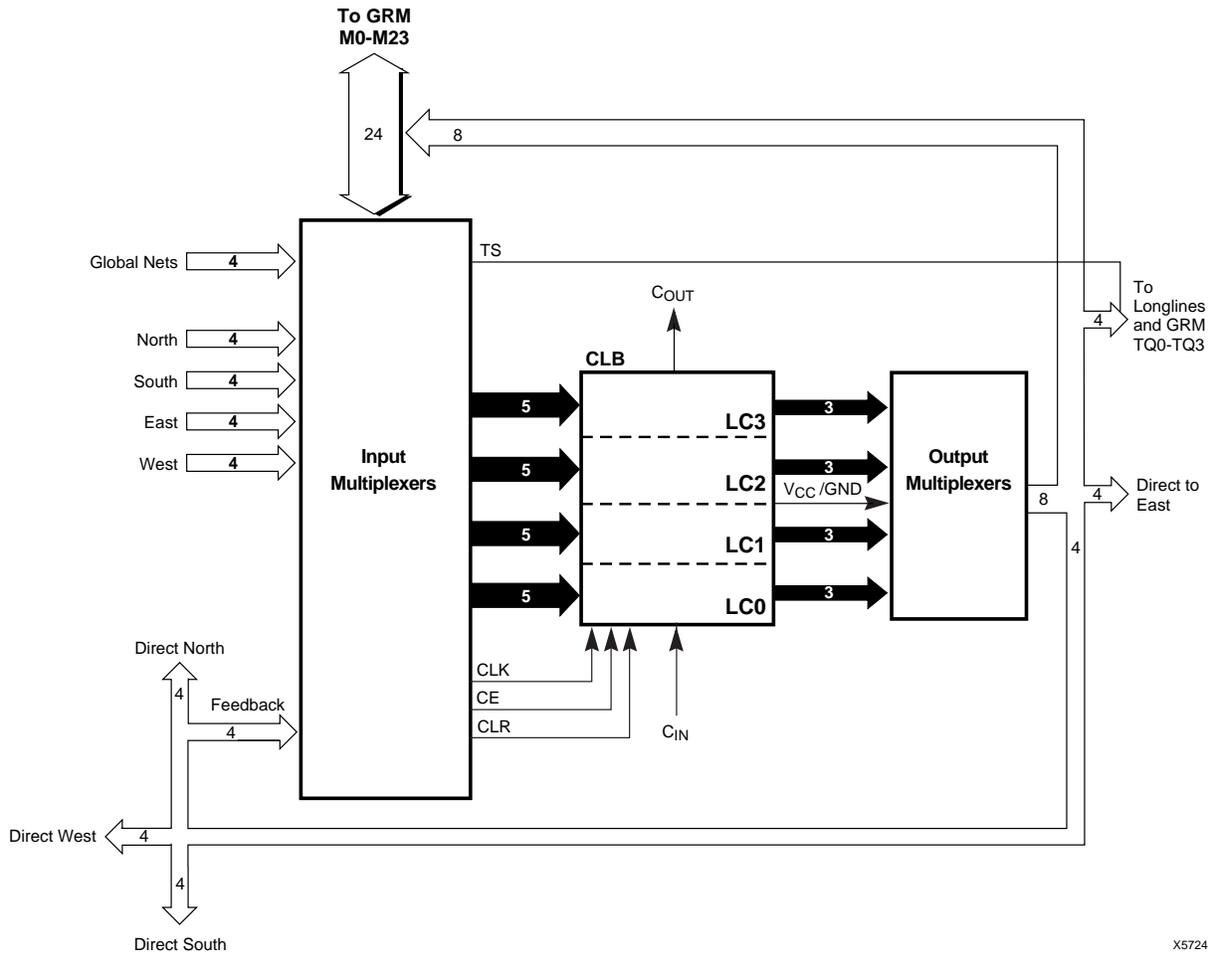


Figure 9: XC5200 3-State Buffers



X5724

Figure 14: VersaBlock Details

CLB inputs have several possible sources: the 24 signals from the GRM, 16 direct connections from neighboring VersaBlocks, four signals from global, low-skew buffers, and the four signals from the CLB output multiplexers. Unlike the output multiplexers, the input multiplexers are not fully populated; i.e., only a subset of the available signals can be connected to a given CLB input. The flexibility of LUT input swapping and LUT mapping compensates for this limitation. For example, if a 2-input NAND gate is required, it can be mapped into any of the four LUTs, and use any two of the four inputs to the LUT.

Direct Connects

The unidirectional direct-connect segments are connected to the logic input/output pins through the CLB input and output multiplexer arrays, and thus bypass the general routing matrix altogether. These lines increase the routing channel utilization, while simultaneously reducing the delay incurred in speed-critical connections.

The direct connects also provide a high-speed path from the edge CLBs to the VersaRing input/output buffers, and thus reduce pin-to-pin set-up time, clock-to-out, and combinational propagation delay. Direct connects from the input buffers to the CLB DI pin (direct flip-flop input) are only available on the left and right edges of the device. CLB look-up table inputs and combinational/registered outputs have direct connects to input/output buffers on all four sides.

The direct connects are ideal for developing customized RPM cells. Using direct connects improves the macro performance, and leaves the other routing channels intact for improved routing. Direct connects can also route through a CLB using one of the four cell-feedthrough paths.

General Routing Matrix

The General Routing Matrix, shown in [Figure 15](#), provides flexible bidirectional connections to the Local Interconnect

segments span the width and height of the chip, respectively.

Two low-skew horizontal and vertical unidirectional global-line segments span each row and column of the chip, respectively.

Single- and Double-Length Lines

The single- and double-length bidirectional line segments make up the bulk of the routing channels. The double-length lines hop across every other CLB to reduce the propagation delays in speed-critical nets. Regenerating the signal strength is recommended after traversing three or four such segments. Xilinx place-and-route software automatically connects buffers in the path of the signal as necessary. Single- and double-length lines cannot drive onto Longlines and global lines; Longlines and global lines can, however, drive onto single- and double-length lines. As a general rule, Longline and global-line connections to the general routing matrix are unidirectional, with the signal direction from these lines toward the routing matrix.

Longlines

Longlines are used for high-fan-out signals, 3-state busses, low-skew nets, and faraway destinations. Row and column splitter PIPs in the middle of the array effectively double the total number of Longlines by electrically dividing them into two separated half-lines. Longlines are driven by the 3-state buffers in each CLB, and are driven by similar buffers at the periphery of the array from the VersaRing I/O Interface.

Bus-oriented designs are easily implemented by using Longlines in conjunction with the 3-state buffers in the CLB and in the VersaRing. Additionally, weak keeper cells at the periphery retain the last valid logic level on the Longlines when all buffers are in 3-state mode.

Longlines connect to the single-length or double-length lines, or to the logic inside the CLB, through the General Routing Matrix. The only manner in which a Longline can be driven is through the four 3-state buffers; therefore, a Longline-to-Longline or single-line-to-Longline connection through PIPs in the General Routing Matrix is not possible. Again, as a general rule, long- and global-line connections to the General Routing Matrix are unidirectional, with the signal direction from these lines toward the routing matrix.

The XC5200 family has no pull-ups on the ends of the Longlines sourced by TBUFs, unlike the XC4000 Series. Consequently, wired functions (i.e., WAND and WORAND) and wide multiplexing functions requiring pull-ups for undefined states (i.e., bus applications) must be implemented in a different way. In the case of the wired functions, the same functionality can be achieved by taking advantage of the

carry/cascade logic described above, implementing a wide logic function in place of the wired function. In the case of 3-state bus applications, the user must insure that all states of the multiplexing function are defined. This process is as simple as adding an additional TBUF to drive the bus High when the previously undefined states are activated.

Global Lines

Global buffers in Xilinx FPGAs are special buffers that drive a dedicated routing network called Global Lines, as shown in Figure 16. This network is intended for high-fanout clocks or other control signals, to maximize speed and minimize skewing while distributing the signal to many loads.

The XC5200 family has a total of four global buffers (BUFG symbol in the library), each with its own dedicated routing channel. Two are distributed vertically and two horizontally throughout the FPGA.

The global lines provide direct input only to the CLB clock pins. The global lines also connect to the General Routing Matrix to provide access from these lines to the function generators and other control signals.

Four clock input pads at the corners of the chip, as shown in Figure 16, provide a high-speed, low-skew clock network to each of the four global-line buffers. In addition to the dedicated pad, the global lines can be sourced by internal logic. PIPs from several routing channels within the VersaRing can also be configured to drive the global-line buffers.

Details of all the programmable interconnect for a CLB is shown in Figure 17.

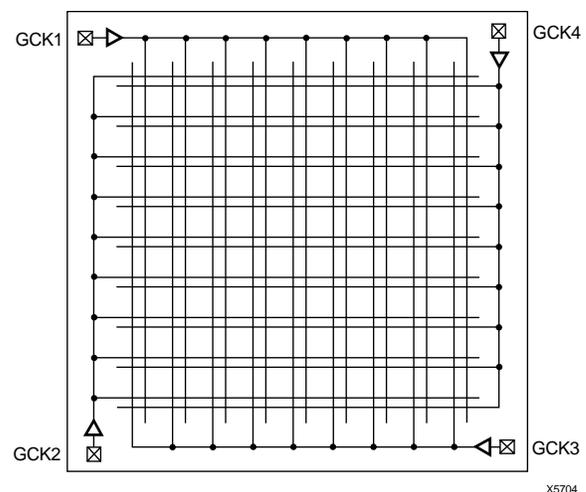


Figure 16: Global Lines

VersaRing Input/Output Interface

The VersaRing, shown in **Figure 18**, is positioned between the core logic and the pad ring; it has all the routing resources of a VersaBlock without the CLB logic. The VersaRing decouples the core logic from the I/O pads. Each VersaRing Cell provides up to four pad-cell connections on one side, and connects directly to the CLB ports on the other side.

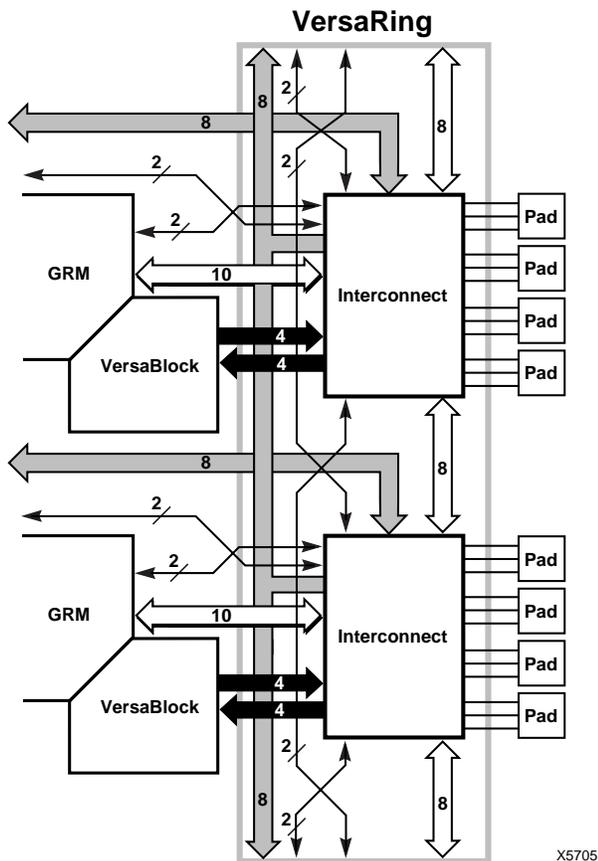


Figure 18: VersaRing I/O Interface

Boundary Scan

The “bed of nails” has been the traditional method of testing electronic assemblies. This approach has become less appropriate, due to closer pin spacing and more sophisticated assembly methods like surface-mount technology and multi-layer boards. The IEEE boundary scan standard 1149.1 was developed to facilitate board-level testing of electronic assemblies. Design and test engineers can imbed a standard test logic structure in their device to achieve high fault coverage for I/O and internal logic. This structure is easily implemented with a four-pin interface on any boundary scan-compatible IC. IEEE 1149.1-compatible devices may be serial daisy-chained together, connected in parallel, or a combination of the two.

XC5200 devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, SAMPLE/PRELOAD, and BYPASS instructions. The TAP can also support two USERCODE instructions. When the boundary scan configuration option is selected, three normal user I/O pins become dedicated inputs for these functions. Another user output pin becomes the dedicated boundary scan output.

Boundary-scan operation is independent of individual IOB configuration and package type. All IOBs are treated as independently controlled bidirectional pins, including any unbonded IOBs. Retaining the bidirectional test capability after configuration provides flexibility for interconnect testing.

Also, internal signals can be captured during EXTEST by connecting them to unbonded IOBs, or to the unused outputs in IOBs used as unidirectional input pins. This technique partially compensates for the lack of INTEST support.

The user can serially load commands and data into these devices to control the driving of their outputs and to examine their inputs. This method is an improvement over bed-of-nails testing. It avoids the need to over-drive device outputs, and it reduces the user interface to four pins. An optional fifth pin, a reset for the control logic, is described in the standard but is not implemented in Xilinx devices.

The dedicated on-chip logic implementing the IEEE 1149.1 functions includes a 16-state machine, an instruction register and a number of data registers. The functional details can be found in the IEEE 1149.1 specification and are also discussed in the Xilinx application note XAPP 017: “Boundary Scan in XC4000 and XC5200 Series devices”

Figure 19 on page 99 is a diagram of the XC5200-Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

The public boundary-scan instructions are always available prior to configuration. After configuration, the public instructions and any USERCODE instructions are only available if specified in the design. While SAMPLE and BYPASS are available during configuration, it is recommended that boundary-scan operations not be performed during this transitory period.

In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA device, and to read back the configuration data.

All of the XC4000 boundary-scan modes are supported in the XC5200 family. Three additional outputs for the User-Register are provided (Reset, Update, and Shift), repre-

senting the decoding of the corresponding state of the boundary-scan internal state machine.

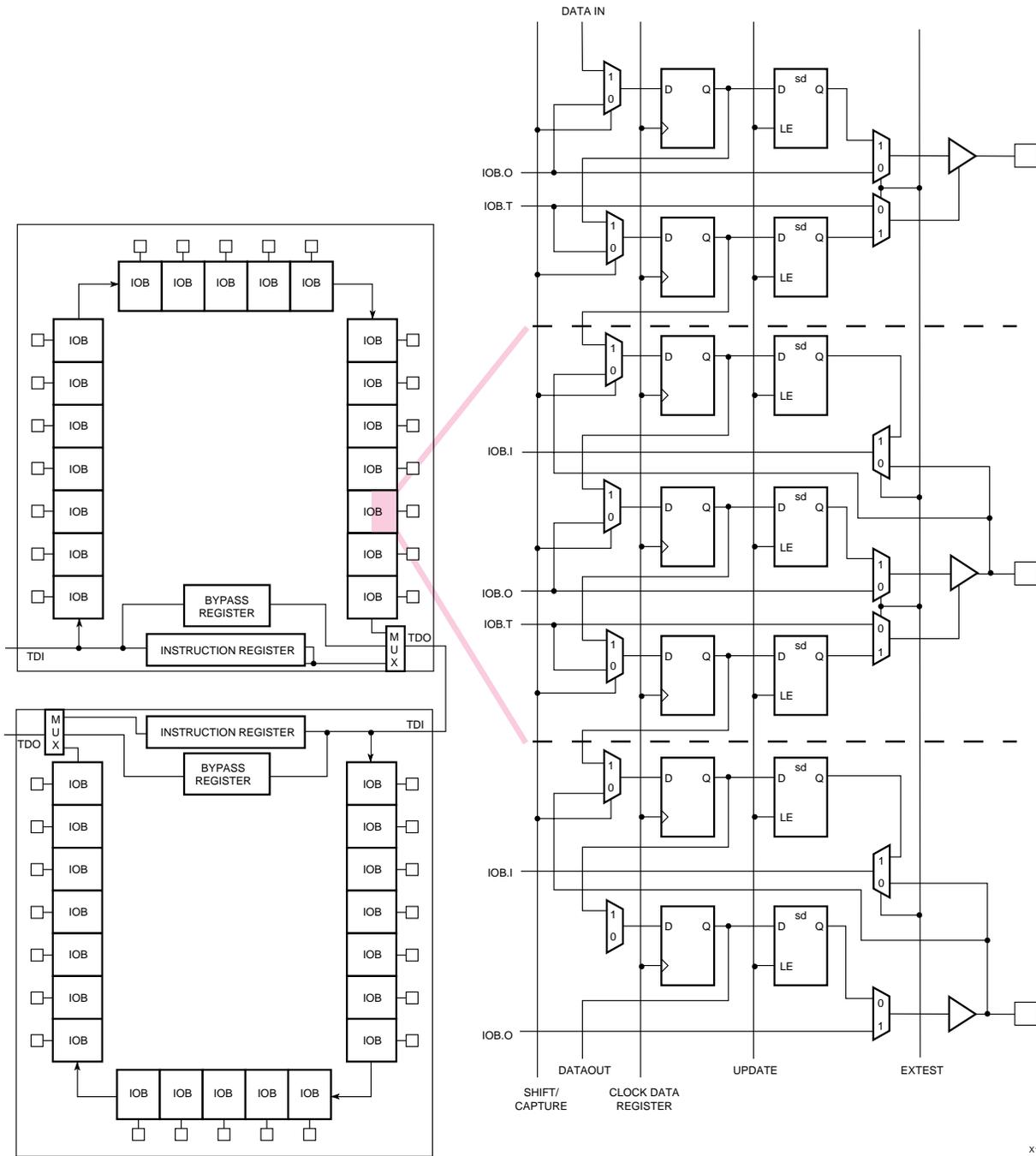


Figure 19: XC5200-Series Boundary Scan Logic

Product Obsolete or Under Obsolescence



Table 9: Pin Descriptions (Continued)

| Pin Name | I/O During Config. | I/O After Config. | Pin Description |
|---|--------------------|-------------------|--|
| TDI, TCK, TMS | I | I/O or I (JTAG) | If boundary scan is used, these pins are Test Data In, Test Clock, and Test Mode Select inputs respectively. They come directly from the pads, bypassing the IOBs. These pins can also be used as inputs to the CLB logic after configuration is completed. If the BSCAN symbol is not placed in the design, all boundary scan functions are inhibited once configuration is completed, and these pins become user-programmable I/O. In this case, they must be called out by special schematic definitions. To use these pins, place the library components TDI, TCK, and TMS instead of the usual pad symbols. Input or output buffers must still be used. |
| HDC | O | I/O | High During Configuration (HDC) is driven High until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, HDC is a user-programmable I/O pin. |
| $\overline{\text{LDC}}$ | O | I/O | Low During Configuration (LDC) is driven Low until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, LDC is a user-programmable I/O pin. |
| $\overline{\text{INIT}}$ | I/O | I/O | Before and during configuration, $\overline{\text{INIT}}$ is a bidirectional signal. A 1 k Ω - 10 k Ω external pull-up resistor is recommended. As an active-Low open-drain output, $\overline{\text{INIT}}$ is held Low during the power stabilization and internal clearing of the configuration memory. As an active-Low input, it can be used to hold the FPGA in the internal WAIT state before the start of configuration. Master mode devices stay in a WAIT state an additional 50 to 250 μs after $\overline{\text{INIT}}$ has gone High. During configuration, a Low on this output indicates that a configuration data error has occurred. After the I/O go active, $\overline{\text{INIT}}$ is a user-programmable I/O pin. |
| GCK1 - GCK4 | Weak Pull-up | I or I/O | Four Global inputs each drive a dedicated internal global net with short delay and minimal skew. These internal global nets can also be driven from internal logic. If not used to drive a global net, any of these pins is a user-programmable I/O pin. The GCK1-GCK4 pins provide the shortest path to the four Global Buffers. Any input pad symbol connected directly to the input of a BUFG symbol is automatically placed on one of these pins. |
| $\overline{\text{CS0}}$, $\overline{\text{CS1}}$, $\overline{\text{WS}}$, $\overline{\text{RS}}$ | I | I/O | These four inputs are used in Asynchronous Peripheral mode. The chip is selected when $\overline{\text{CS0}}$ is Low and $\overline{\text{CS1}}$ is High. While the chip is selected, a Low on Write Strobe ($\overline{\text{WS}}$) loads the data present on the D0 - D7 inputs into the internal data buffer. A Low on Read Strobe ($\overline{\text{RS}}$) changes D7 into a status output — High if Ready, Low if Busy — and drives D0 - D6 High. In Express mode, $\overline{\text{CS1}}$ is used as a serial-enable signal for daisy-chaining. $\overline{\text{WS}}$ and $\overline{\text{RS}}$ should be mutually exclusive, but if both are Low simultaneously, the Write Strobe overrides. After configuration, these are user-programmable I/O pins. |
| A0 - A17 | O | I/O | During Master Parallel configuration, these 18 output pins address the configuration EPROM. After configuration, they are user-programmable I/O pins. |
| D0 - D7 | I | I/O | During Master Parallel, Peripheral, and Express configuration, these eight input pins receive configuration data. After configuration, they are user-programmable I/O pins. |
| DIN | I | I/O | During Slave Serial or Master Serial configuration, DIN is the serial configuration data input receiving data on the rising edge of CCLK. During Parallel configuration, DIN is the D0 input. After configuration, DIN is a user-programmable I/O pin. |
| DOUT | O | I/O | During configuration in any mode but Express mode, DOUT is the serial configuration data output that can drive the DIN of daisy-chained slave FPGAs. DOUT data changes on the falling edge of CCLK. In Express mode, DOUT is the status output that can drive the $\overline{\text{CS1}}$ of daisy-chained FPGAs, to enable and disable downstream devices. After configuration, DOUT is a user-programmable I/O pin. |

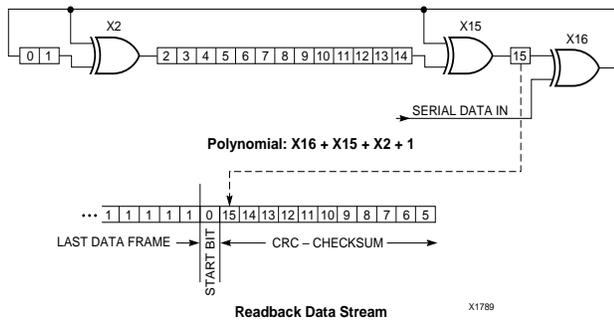


Figure 23: Circuit for Generating CRC-16

Configuration Sequence

There are four major steps in the XC5200-Series power-up configuration sequence.

- Power-On Time-Out
- Initialization
- Configuration
- Start-Up

The full process is illustrated in Figure 24.

Power-On Time-Out

An internal power-on reset circuit is triggered when power is applied. When V_{CC} reaches the voltage at which portions of the FPGA begin to operate (i.e., performs a write-and-read test of a sample pair of configuration memory bits), the programmable I/O buffers are 3-stated with active high-impedance pull-up resistors. A time-out delay — nominally 4 ms — is initiated to allow the power-supply voltage to stabilize. For correct operation the power supply must reach $V_{CC}(\text{min})$ by the end of the time-out, and must not dip below it thereafter.

There is no distinction between master and slave modes with regard to the time-out delay. Instead, the INIT line is used to ensure that all daisy-chained devices have completed initialization. Since XC2000 devices do not have this signal, extra care must be taken to guarantee proper operation when daisy-chaining them with XC5200 devices. For proper operation with XC3000 devices, the RESET signal, which is used in XC3000 to delay configuration, should be connected to INIT.

If the time-out delay is insufficient, configuration should be delayed by holding the INIT pin Low until the power supply has reached operating levels.

This delay is applied only on power-up. It is not applied when reconfiguring an FPGA by pulsing the PROGRAM pin Low. During all three phases — Power-on, Initialization, and Configuration — DONE is held Low; HDC, LDC, and INIT are active; DOUT is driven; and all I/O buffers are disabled.

Initialization

This phase clears the configuration memory and establishes the configuration mode.

The configuration memory is cleared at the rate of one frame per internal clock cycle (nominally 1 MHz). An open-drain bidirectional signal, INIT, is released when the configuration memory is completely cleared. The device then tests for the absence of an external active-low level on INIT. The mode lines are sampled two internal clock cycles later (nominally 2 μs).

The master device waits an additional 32 μs to 256 μs (nominally 64-128 μs) to provide adequate time for all of the slave devices to recognize the release of INIT as well. Then the master device enters the Configuration phase.

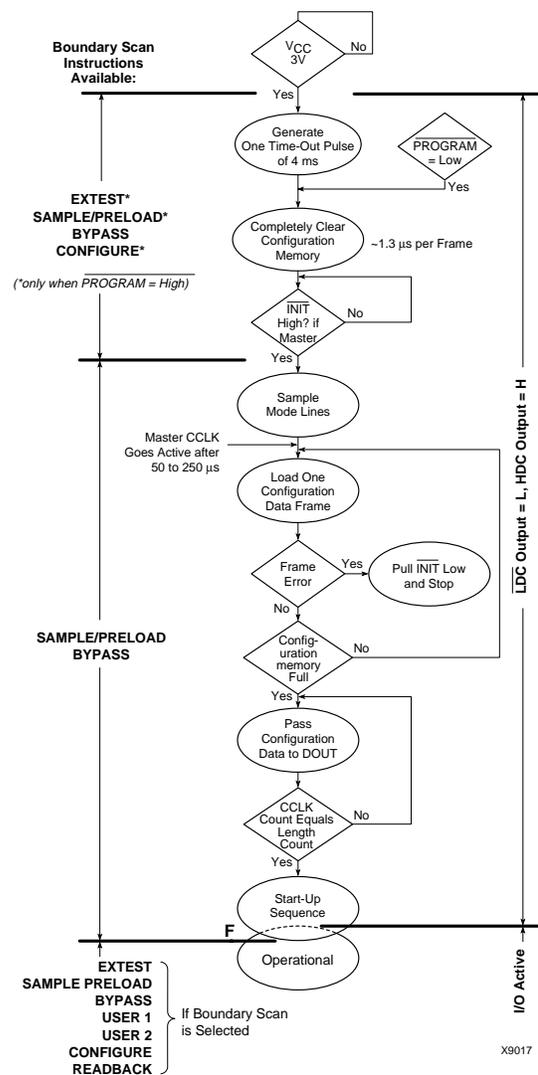


Figure 24: Configuration Sequence

When the UCLK_SYNC option is enabled, the user can externally hold the open-drain DONE output Low, and thus stall all further progress in the start-up sequence until DONE is released and has gone High. This option can be used to force synchronization of several FPGAs to a common user clock, or to guarantee that all devices are successfully configured before any I/Os go active.

If either of these two options is selected, and no user clock is specified in the design or attached to the device, the chip could reach a point where the configuration of the device is complete and the Done pin is asserted, but the outputs do not become active. The solution is either to recreate the bitstream specifying the start-up clock as CCLK, or to supply the appropriate user clock.

Start-up Sequence

The Start-up sequence begins when the configuration memory is full, and the total number of configuration clocks received since INIT went High equals the loaded value of the length count.

The next rising clock edge sets a flip-flop Q0, shown in [Figure 26](#). Q0 is the leading bit of a 5-bit shift register. The outputs of this register can be programmed to control three events.

- The release of the open-drain DONE output
- The change of configuration-related pins to the user function, activating all IOBs.
- The termination of the global Set/Reset initialization of all CLB and IOB storage elements.

The DONE pin can also be wire-ANDed with DONE pins of other FPGAs or with other external signals, and can then be used as input to bit Q3 of the start-up register. This is called “Start-up Timing Synchronous to Done In” and is selected by either CCLK_SYNC or UCLK_SYNC.

When DONE is not used as an input, the operation is called “Start-up Timing Not Synchronous to DONE In,” and is selected by either CCLK_NOSYNC or UCLK_NOSYNC.

As a configuration option, the start-up control register beyond Q0 can be clocked either by subsequent CCLK pulses or from an on-chip user net called STARTUP.CLK. These signals can be accessed by placing the STARTUP library symbol.

Start-up from CCLK

If CCLK is used to drive the start-up, Q0 through Q3 provide the timing. Heavy lines in [Figure 25](#) show the default timing, which is compatible with XC2000 and XC3000 devices using early DONE and late Reset. The thin lines indicate all other possible timing options.

Start-up from a User Clock (STARTUP.CLK)

When, instead of CCLK, a user-supplied start-up clock is selected, Q1 is used to bridge the unknown phase relation-

ship between CCLK and the user clock. This arbitration causes an unavoidable one-cycle uncertainty in the timing of the rest of the start-up sequence.

DONE Goes High to Signal End of Configuration

In all configuration modes except Express mode, XC5200-Series devices read the expected length count from the bitstream and store it in an internal register. The length count varies according to the number of devices and the composition of the daisy chain. Each device also counts the number of CCLKs during configuration.

Two conditions have to be met in order for the DONE pin to go high:

- the chip's internal memory must be full, and
- the configuration length count must be met, *exactly*.

This is important because the counter that determines when the length count is met begins with the very first CCLK, not the first one after the preamble.

Therefore, if a stray bit is inserted before the preamble, or the data source is not ready at the time of the first CCLK, the internal counter that holds the number of CCLKs will be one ahead of the actual number of data bits read. At the end of configuration, the configuration memory will be full, but the number of bits in the internal counter will not match the expected length count.

As a consequence, a Master mode device will continue to send out CCLKs until the internal counter turns over to zero, and then reaches the correct length count a second time. This will take several seconds [$2^{24} * \text{CCLK period}$] — which is sometimes interpreted as the device not configuring at all.

If it is not possible to have the data ready at the time of the first CCLK, the problem can be avoided by increasing the number in the length count by the appropriate value.

In Express mode, there is no length count. The DONE pin for each device goes High when the device has received its quota of configuration data. Wiring the DONE pins of several devices together delays start-up of all devices until all are fully configured.

Note that DONE is an open-drain output and does not go High unless an internal pull-up is activated or an external pull-up is attached. The internal pull-up is activated as the default by the bitstream generation software.

Release of User I/O After DONE Goes High

By default, the user I/O are released one CCLK cycle after the DONE pin goes High. If CCLK is not clocked after DONE goes High, the outputs remain in their initial state — 3-stated, with a 20 k Ω - 100 k Ω pull-up. The delay from

Asynchronous Peripheral Mode

Write to FPGA

Asynchronous Peripheral mode uses the trailing edge of the logic AND condition of \overline{WS} and $\overline{CS0}$ being Low and \overline{RS} and $\overline{CS1}$ being High to accept byte-wide data from a microprocessor bus. In the lead FPGA, this data is loaded into a double-buffered UART-like parallel-to-serial converter and is serially shifted into the internal logic.

The lead FPGA presents the preamble data (and all data that overflows the lead device) on its DOUT pin. The RDY/BUSY output from the lead FPGA acts as a handshake signal to the microprocessor. RDY/BUSY goes Low when a byte has been received, and goes High again when the byte-wide input buffer has transferred its information into the shift register, and the buffer is ready to receive new data. A new write may be started immediately, as soon as the RDY/BUSY output has gone Low, acknowledging receipt of the previous data. Write may not be terminated until RDY/BUSY is High again for one CCLK period. Note that RDY/BUSY is pulled High with a high-impedance pull-up prior to INIT going High.

The length of the BUSY signal depends on the activity in the UART. If the shift register was empty when the new byte was received, the BUSY signal lasts for only two CCLK periods. If the shift register was still full when the new byte was received, the BUSY signal can be as long as nine CCLK periods.

Note that after the last byte has been entered, only seven of its bits are shifted out. CCLK remains High with DOUT equal to bit 6 (the next-to-last bit) of the last byte entered.

The $\overline{RDY}/\overline{BUSY}$ handshake can be ignored if the delay from any one Write to the end of the next Write is guaranteed to be longer than 10 CCLK periods.

Status Read

The logic AND condition of the $\overline{CS0}$, $\overline{CS1}$ and \overline{RS} inputs puts the device status on the Data bus.

- D7 High indicates Ready
- D7 Low indicates Busy
- D0 through D6 go unconditionally High

It is mandatory that the whole start-up sequence be started and completed by one byte-wide input. Otherwise, the pins used as Write Strobe or Chip Enable might become active outputs and interfere with the final byte transfer. If this transfer does not occur, the start-up sequence is not completed all the way to the finish (point F in Figure 25 on page 109).

In this case, at worst, the internal reset is not released. At best, Readback and Boundary Scan are inhibited. The length-count value, as generated by the software, ensures that these problems never occur.

Although RDY/BUSY is brought out as a separate signal, microprocessors can more easily read this information on one of the data lines. For this purpose, D7 represents the RDY/BUSY status when \overline{RS} is Low, \overline{WS} is High, and the two chip select lines are both active.

Asynchronous Peripheral mode is selected by a <101> on the mode pins (M2, M1, M0).

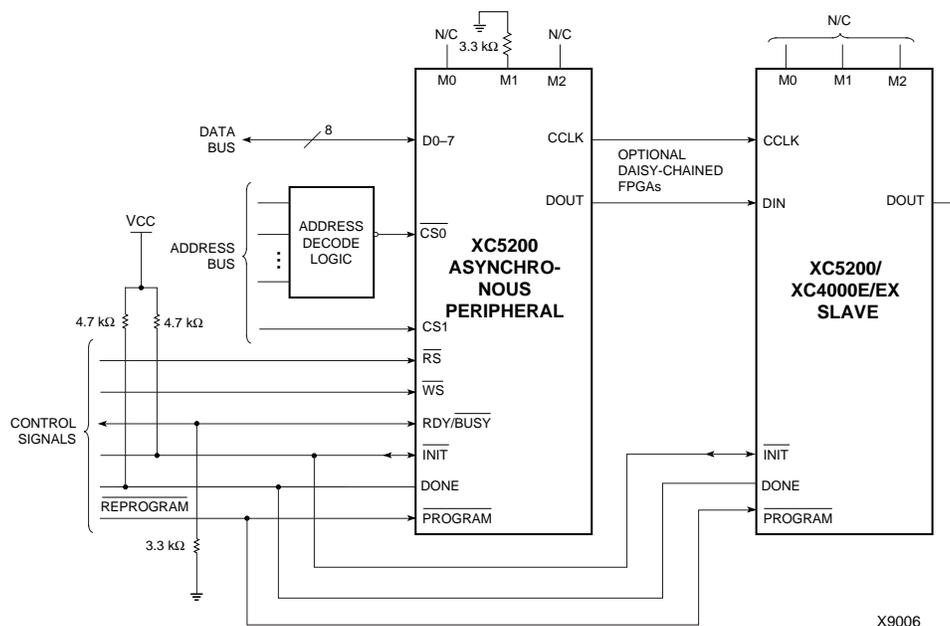


Figure 35: Asynchronous Peripheral Mode Circuit Diagram

XC5200 Switching Characteristics

Definition of Terms

In the following tables, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

Advance: Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or device families. Use as estimates, not for production.

Preliminary: Based on preliminary characterization. Further changes are not expected.

Unmarked: Specifications not identified as either Advance or Preliminary are to be considered Final.¹

XC5200 Operating Conditions

| Symbol | Description | Min | Max | Units |
|------------------|--|------|-----------------|-----------------|
| V _{CC} | Supply voltage relative to GND Commercial: 0°C to 85°C junction | 4.75 | 5.25 | V |
| | Supply voltage relative to GND Industrial: -40°C to 100°C junction | 4.5 | 5.5 | V |
| V _{IHT} | High-level input voltage — TTL configuration | 2.0 | V _{CC} | V |
| V _{ILT} | Low-level input voltage — TTL configuration | 0 | 0.8 | V |
| V _{IHC} | High-level input voltage — CMOS configuration | 70% | 100% | V _{CC} |
| V _{ILC} | Low-level input voltage — CMOS configuration | 0 | 20% | V _{CC} |
| T _{IN} | Input signal transition time | | 250 | ns |

XC5200 DC Characteristics Over Operating Conditions

| Symbol | Description | Min | Max | Units |
|------------------|--|------|------|-------|
| V _{OH} | High-level output voltage @ I _{OH} = -8.0 mA, V _{CC} min | 3.86 | | V |
| V _{OL} | Low-level output voltage @ I _{OL} = 8.0 mA, V _{CC} max | | 0.4 | V |
| I _{CCO} | Quiescent FPGA supply current (Note 1) | | 15 | mA |
| I _{IL} | Leakage current | -10 | +10 | μA |
| C _{IN} | Input capacitance (sample tested) | | 15 | pF |
| I _{RIN} | Pad pull-up (when selected) @ V _{IN} = 0V (sample tested) | 0.02 | 0.30 | mA |

Note: 1. With no output current loads, all package pins at V_{CC} or GND, either TTL or CMOS inputs, and the FPGA configured with a tie option.

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XC5200 Absolute Maximum Ratings

| Symbol | Description | | Units |
|------------------|--|------------------------------|-------|
| V _{CC} | Supply voltage relative to GND | -0.5 to +7.0 | V |
| V _{IN} | Input voltage with respect to GND | -0.5 to V _{CC} +0.5 | V |
| V _{TS} | Voltage applied to 3-state output | -0.5 to V _{CC} +0.5 | V |
| T _{STG} | Storage temperature (ambient) | -65 to +150 | °C |
| T _{SOL} | Maximum soldering temperature (10 s @ 1/16 in. = 1.5 mm) | +260 | °C |
| T _J | Junction temperature in plastic packages | +125 | °C |
| | Junction temperature in ceramic packages | +150 | °C |

Note: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.

1. Notwithstanding the definition of the above terms, all specifications are subject to change without notice.

Product Obsolete or Under Obsolescence



XC5200 CLB Switching Characteristic Guidelines

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the timing calculator and used in the simulator.

| Speed Grade | | -6 | | -5 | | -4 | | -3 | |
|---|---------------|----------|----------|----------|----------|----------|----------|----------|----------|
| Description | Symbol | Min (ns) | Max (ns) |
| Combinatorial Delays | | | | | | | | | |
| F inputs to X output | T_{ILO} | | 5.6 | | 4.6 | | 3.8 | | 3.0 |
| F inputs via transparent latch to Q | T_{ITO} | | 8.0 | | 6.6 | | 5.4 | | 4.3 |
| DI inputs to DO output (Logic-Cell Feedthrough) | T_{IDO} | | 4.3 | | 3.5 | | 2.8 | | 2.4 |
| F inputs via F5_MUX to DO output | T_{IMO} | | 7.2 | | 5.8 | | 5.0 | | 4.3 |
| Carry Delays | | | | | | | | | |
| Incremental delay per bit | T_{CY} | | 0.7 | | 0.6 | | 0.5 | | 0.5 |
| Carry-in overhead from DI | T_{CYDI} | | 1.8 | | 1.6 | | 1.5 | | 1.4 |
| Carry-in overhead from F | T_{CYL} | | 3.7 | | 3.2 | | 2.9 | | 2.4 |
| Carry-out overhead to DO | T_{CYO} | | 4.0 | | 3.2 | | 2.5 | | 2.1 |
| Sequential Delays | | | | | | | | | |
| Clock (CK) to out (Q) (Flip-Flop) | T_{CKO} | | 5.8 | | 4.9 | | 4.0 | | 4.0 |
| Gate (Latch enable) going active to out (Q) | T_{GO} | | 9.2 | | 7.4 | | 5.9 | | 5.5 |
| Set-up Time Before Clock (CK) | | | | | | | | | |
| F inputs | T_{ICK} | 2.3 | | 1.8 | | 1.4 | | 1.3 | |
| F inputs via F5_MUX | T_{MICK} | 3.8 | | 3.0 | | 2.5 | | 2.4 | |
| DI input | T_{DICK} | 0.8 | | 0.5 | | 0.4 | | 0.4 | |
| CE input | T_{EICK} | 1.6 | | 1.2 | | 0.9 | | 0.9 | |
| Hold Times After Clock (CK) | | | | | | | | | |
| F inputs | T_{CKI} | 0 | | 0 | | 0 | | 0 | |
| F inputs via F5_MUX | T_{CKMI} | 0 | | 0 | | 0 | | 0 | |
| DI input | T_{CKDI} | 0 | | 0 | | 0 | | 0 | |
| CE input | T_{CKEI} | 0 | | 0 | | 0 | | 0 | |
| Clock Widths | | | | | | | | | |
| Clock High Time | T_{CH} | 6.0 | | 6.0 | | 6.0 | | 6.0 | |
| Clock Low Time | T_{CL} | 6.0 | | 6.0 | | 6.0 | | 6.0 | |
| Toggle Frequency (MHz) (Note 3) | F_{TOG} | | 83 | | 83 | | 83 | | 83 |
| Reset Delays | | | | | | | | | |
| Width (High) | $T_{CLR\ W}$ | 6.0 | | 6.0 | | 6.0 | | 6.0 | |
| Delay from CLR to Q (Flip-Flop) | T_{CLR} | | 7.7 | | 6.3 | | 5.1 | | 4.0 |
| Delay from CLR to Q (Latch) | $T_{CLR\ L}$ | | 6.5 | | 5.2 | | 4.2 | | 3.0 |
| Global Reset Delays | | | | | | | | | |
| Width (High) | $T_{GCLR\ W}$ | 6.0 | | 6.0 | | 6.0 | | 6.0 | |
| Delay from internal GR to Q | T_{GCLR} | | 14.7 | | 12.1 | | 9.1 | | 8.0 |

- Note:**
1. The CLB K to Q output delay (T_{CKO}) of any CLB, plus the shortest possible interconnect delay, is always longer than the Data In hold-time requirement (T_{CKDI}) of any CLB on the same die.
 2. Timing is based upon the XC5215 device. For other devices, see Timing Calculator.
 3. Maximum flip-flop toggle rate for export control purposes.

XC5200 Guaranteed Input and Output Parameters (Pin-to-Pin)

All values listed below are tested directly, and guaranteed over the operating conditions. The same parameters can also be derived indirectly from the Global Buffer specifications. The delay calculator uses this indirect method, and may overestimate because of worst-case assumptions. When there is a discrepancy between these two methods, the values listed below should be used, and the derived values should be considered conservative overestimates.

| | | Speed Grade | -6 | -5 | -4 | -3 |
|--|--------------------------|-------------|----------|----------|----------|----------|
| Description | Symbol | Device | Max (ns) | Max (ns) | Max (ns) | Max (ns) |
| Global Clock to Output Pad (fast) | T_{ICKOF} (Max) | XC5202 | 16.9 | 15.1 | 10.9 | 9.8 |
| | | XC5204 | 17.1 | 15.3 | 11.3 | 9.9 |
| | | XC5206 | 17.2 | 15.4 | 11.9 | 10.8 |
| | | XC5210 | 17.2 | 15.4 | 12.8 | 11.2 |
| | | XC5215 | 19.0 | 17.0 | 12.8 | 11.7 |
| Global Clock to Output Pad (slew-limited) | T_{ICKO} (Max) | XC5202 | 21.4 | 18.7 | 12.6 | 11.5 |
| | | XC5204 | 21.6 | 18.9 | 13.3 | 11.9 |
| | | XC5206 | 21.7 | 19.0 | 13.6 | 12.5 |
| | | XC5210 | 21.7 | 19.0 | 15.0 | 12.9 |
| | | XC5215 | 24.3 | 21.2 | 15.0 | 13.1 |
| Input Set-up Time (no delay) to CLB Flip-Flop | T_{PSUF} (Min) | XC5202 | 2.5 | 2.0 | 1.9 | 1.9 |
| | | XC5204 | 2.3 | 1.9 | 1.9 | 1.9 |
| | | XC5206 | 2.2 | 1.9 | 1.9 | 1.9 |
| | | XC5210 | 2.2 | 1.9 | 1.9 | 1.8 |
| | | XC5215 | 2.0 | 1.8 | 1.7 | 1.7 |
| Input Hold Time (no delay) to CLB Flip-Flop | T_{PHF} (Min) | XC5202 | 3.8 | 3.8 | 3.5 | 3.5 |
| | | XC5204 | 3.9 | 3.9 | 3.8 | 3.6 |
| | | XC5206 | 4.4 | 4.4 | 4.4 | 4.3 |
| | | XC5210 | 5.1 | 5.1 | 4.9 | 4.8 |
| | | XC5215 | 5.8 | 5.8 | 5.7 | 5.6 |
| Input Set-up Time (with delay) to CLB Flip-Flop DI Input | T_{PSU} | XC5202 | 7.3 | 6.6 | 6.6 | 6.6 |
| | | XC5204 | 7.3 | 6.6 | 6.6 | 6.6 |
| | | XC5206 | 7.2 | 6.5 | 6.4 | 6.3 |
| | | XC5210 | 7.2 | 6.5 | 6.0 | 6.0 |
| | | XC5215 | 6.8 | 5.7 | 5.7 | 5.7 |
| Input Set-up Time (with delay) to CLB Flip-Flop F Input | T_{PSUL} (Min) | XC5202 | 8.8 | 7.7 | 7.5 | 7.5 |
| | | XC5204 | 8.6 | 7.5 | 7.5 | 7.5 |
| | | XC5206 | 8.5 | 7.4 | 7.4 | 7.4 |
| | | XC5210 | 8.5 | 7.4 | 7.4 | 7.3 |
| | | XC5215 | 8.5 | 7.4 | 7.4 | 7.2 |
| Input Hold Time (with delay) to CLB Flip-Flop | T_{PH} (Min) | XC52xx | 0 | 0 | 0 | 0 |

- Note:**
- These measurements assume that the CLB flip-flop uses a direct interconnect to or from the IOB. The INREG/ OUTREG properties, or XACT-Performance, can be used to assure that direct connects are used. t_{PSU} applies only to the CLB input DI that bypasses the look-up table, which only offers direct connects to IOBs on the left and right edges of the die. t_{PSUL} applies to the CLB inputs F that feed the look-up table, which offers direct connect to IOBs on all four edges, as do the CLB Q outputs.
 - When testing outputs (fast or slew-limited), half of the outputs on one side of the device are switching.

Product Obsolete or Under Obsolescence

XC5200 Series Field Programmable Gate Arrays



XC5200 Boundary Scan (JTAG) Switching Characteristic Guidelines

The following guidelines reflect worst-case values over the recommended operating conditions. They are expressed in units of nanoseconds and apply to all XC5200 devices unless otherwise noted.

| Speed Grade | | -6 | | -5 | | -4 | | -3 | |
|--|--------------|------|------|------|------|------|------|------|------|
| Description | Symbol | Min | Max | Min | Max | Min | Max | Min | Max |
| Setup and Hold | | | | | | | | | |
| Input (TDI) to clock (TCK) setup time | T_{TDITCK} | 30.0 | | 30.0 | | 30.0 | | 30.0 | |
| Input (TDI) to clock (TCK) hold time | T_{TCKTDI} | 0 | | 0 | | 0 | | 0 | |
| Input (TMS) to clock (TCK) setup time | T_{TMSTCK} | 15.0 | | 15.0 | | 15.0 | | 15.0 | |
| Input (TMS) to clock (TCK) hold time | T_{TCKTMS} | 0 | | 0 | | 0 | | 0 | |
| Propagation Delay | | | | | | | | | |
| Clock (TCK) to Pad (TDO) | T_{TCKPO} | | 30.0 | | 30.0 | | 30.0 | | 30.0 |
| Clock | | | | | | | | | |
| Clock (TCK) High | T_{TCKH} | 30.0 | | 30.0 | | 30.0 | | 30.0 | |
| Clock (TCK) Low | T_{TCKL} | 30.0 | | 30.0 | | 30.0 | | 30.0 | |
| F_{MAX} (MHz) | F_{MAX} | | 10.0 | | 10.0 | | 10.0 | | 10.0 |

Note 1: Input pad setup and hold times are specified with respect to the internal clock.

Product Obsolete or Under Obsolescence

XC5200 Series Field Programmable Gate Arrays



| Pin | Description | PC84 | PQ100 | VQ100 | TQ144 | PG156 | PQ160 | Boundary Scan Order |
|------|----------------------------|------|-------|-------|-------|-------|-------|---------------------|
| 99. | I/O | 68 | 72 | 69 | 97 | T5 | 107 | 486 |
| 100. | I/O | - | - | - | 98 | R6 | 108 | 492 |
| 101. | I/O | - | - | - | 99 | T4 | 109 | 495 |
| | GND | - | - | - | 100 | P6 | 110 | - |
| 102. | I/O (D1) | 69 | 73 | 70 | 101 | T3 | 113 | 498 |
| 103. | I/O (RCLK-BUSY/RDY) | 70 | 74 | 71 | 102 | P5 | 114 | 504 |
| 104. | I/O | - | - | - | 103 | R4 | 115 | 507 |
| 105. | I/O | - | - | - | 104 | R3 | 116 | 510 |
| 106. | I/O (D0, DIN) | 71 | 75 | 72 | 105 | P4 | 117 | 516 |
| 107. | I/O (DOU) | 72 | 76 | 73 | 106 | T2 | 118 | 519 |
| | CCLK | 73 | 77 | 74 | 107 | R2 | 119 | - |
| | VCC | 74 | 78 | 75 | 108 | P3 | 120 | - |
| 108. | I/O (TDO) | 75 | 79 | 76 | 109 | T1 | 121 | 0 |
| | GND | 76 | 80 | 77 | 110 | N3 | 122 | - |
| 109. | I/O (A0, \overline{WS}) | 77 | 81 | 78 | 111 | R1 | 123 | 9 |
| 110. | GCK4 (A1, I/O) | 78 | 82 | 79 | 112 | P2 | 124 | 15 |
| 111. | I/O | - | - | - | 113 | N2 | 125 | 18 |
| 112. | I/O | - | - | - | 114 | M3 | 126 | 21 |
| 113. | I/O (A2, CS1) | 79 | 83 | 80 | 115 | P1 | 127 | 27 |
| 114. | I/O (A3) | 80 | 84 | 81 | 116 | N1 | 128 | 30 |
| 115. | I/O | - | - | - | 117 | M2 | 129 | 33 |
| 116. | I/O | - | - | - | - | M1 | 130 | 39 |
| | GND | - | - | - | 118 | L3 | 131 | - |
| 117. | I/O | - | - | - | 119 | L2 | 132 | 42 |
| 118. | I/O | - | - | - | 120 | L1 | 133 | 45 |
| 119. | I/O (A4) | 81 | 85 | 82 | 121 | K3 | 134 | 51 |
| 120. | I/O (A5) | 82 | 86 | 83 | 122 | K2 | 135 | 54 |
| 121. | I/O | - | 87 | 84 | 123 | K1 | 137 | 57 |
| 122. | I/O | - | 88 | 85 | 124 | J1 | 138 | 63 |
| 123. | I/O (A6) | 83 | 89 | 86 | 125 | J2 | 139 | 66 |
| 124. | I/O (A7) | 84 | 90 | 87 | 126 | J3 | 140 | 69 |
| | GND | 1 | 91 | 88 | 127 | H2 | 141 | - |

Additional No Connect (N.C.) Connections for PQ160 Package

| PQ160 | | | | |
|-------|----|----|-----|-----|
| 8 | 30 | 89 | 111 | 136 |
| 9 | 31 | 90 | 112 | |

Notes: Boundary Scan Bit 0 = TDO.T
 Boundary Scan Bit 1 = TDO.O
 Boundary Scan Bit 1056 = BSCAN.UPD

Product Obsolete or Under Obsolescence

XC5200 Series Field Programmable Gate Arrays



| Pin | Description | PC84 | PQ100 | VQ100 | TQ144 | PQ160 | TQ176 | PG191 | PQ208 | Boundary Scan Order |
|------|----------------------------|------|-------|-------|-------|-------|-------|-------|-------|---------------------|
| | CCLK | 73 | 77 | 74 | 107 | 119 | 131 | V1 | 153 | - |
| | VCC | 74 | 78 | 75 | 108 | 120 | 132 | R4 | 154 | - |
| 130. | I/O (TDO) | 75 | 79 | 76 | 109 | 121 | 133 | U2 | 159 | - |
| | GND | 76 | 80 | 77 | 110 | 122 | 134 | R3 | 160 | - |
| 131. | I/O (A0, \overline{WS}) | 77 | 81 | 78 | 111 | 123 | 135 | T3 | 161 | 9 |
| 132. | GCK4 (A1, I/O) | 78 | 82 | 79 | 112 | 124 | 136 | U1 | 162 | 15 |
| 133. | I/O | - | - | - | 113 | 125 | 137 | P3 | 163 | 18 |
| 134. | I/O | - | - | - | 114 | 126 | 138 | R2 | 164 | 21 |
| 135. | I/O (A2, CS1) | 79 | 83 | 80 | 115 | 127 | 139 | T2 | 165 | 27 |
| 136. | I/O (A3) | 80 | 84 | 81 | 116 | 128 | 140 | N3 | 166 | 30 |
| 137. | I/O | - | - | - | 117 | 129 | 141 | P2 | 167 | 33 |
| 138. | I/O | - | - | - | - | 130 | 142 | T1 | 168 | 42 |
| | GND | - | - | - | 118 | 131 | 143 | M3 | 171 | - |
| 139. | I/O | - | - | - | 119 | 132 | 144 | P1 | 172 | 45 |
| 140. | I/O | - | - | - | 120 | 133 | 145 | N1 | 173 | 51 |
| 141. | I/O (A4) | 81 | 85 | 82 | 121 | 134 | 146 | M2 | 174 | 54 |
| 142. | I/O (A5) | 82 | 86 | 83 | 122 | 135 | 147 | M1 | 175 | 57 |
| 143. | I/O | - | - | - | - | - | 148 | L3 | 176 | 63 |
| 144. | I/O | - | - | - | - | 136 | 149 | L2 | 177 | 66 |
| 145. | I/O | - | 87 | 84 | 123 | 137 | 150 | L1 | 178 | 69 |
| 146. | I/O | - | 88 | 85 | 124 | 138 | 151 | K1 | 179 | 75 |
| 147. | I/O (A6) | 83 | 89 | 86 | 125 | 139 | 152 | K2 | 180 | 78 |
| 148. | I/O (A7) | 84 | 90 | 87 | 126 | 140 | 153 | K3 | 181 | 81 |
| | GND | 1 | 91 | 88 | 127 | 141 | 154 | K4 | 182 | - |

Additional No Connect (N.C.) Connections for PQ208 and TQ176 Packages

| PQ208 | | | | | | | TQ176 |
|-------|----|----|-----|-----|-----|-----|-------|
| 195 | 1 | 39 | 65 | 104 | 143 | 158 | 167 |
| 196 | 3 | 51 | 66 | 105 | 144 | 169 | |
| 206 | 12 | 52 | 91 | 107 | 155 | 170 | |
| 207 | 13 | 53 | 92 | 117 | 156 | | |
| 208 | 38 | 54 | 102 | 118 | 157 | | |

Notes: Boundary Scan Bit 0 = TDO.T
 Boundary Scan Bit 1 = TDO.O
 Boundary Scan Bit 1056 = BSCAN.UPD

Pin Locations for XC5210 Devices

The following table may contain pinout information for unsupported device/package combinations. Please see the availability charts elsewhere in the XC5200 Series data sheet for availability information.

| Pin | Description | PC84 | TQ144 | PQ160 | TQ176 | PQ208 | PG223 | BG225 | PQ240 | Boundary Scan Order |
|-----|-------------|------|-------|-------|-------|-------|-------|-------|-------|---------------------|
| | VCC | 2 | 128 | 142 | 155 | 183 | J4 | VCC* | 212 | - |
| 1. | I/O (A8) | 3 | 129 | 143 | 156 | 184 | J3 | E8 | 213 | 111 |
| 2. | I/O (A9) | 4 | 130 | 144 | 157 | 185 | J2 | B7 | 214 | 114 |
| 3. | I/O | - | 131 | 145 | 158 | 186 | J1 | A7 | 215 | 117 |
| 4. | I/O | - | 132 | 146 | 159 | 187 | H1 | C7 | 216 | 123 |
| 5. | I/O | - | - | - | 160 | 188 | H2 | D7 | 217 | 126 |
| 6. | I/O | - | - | - | 161 | 189 | H3 | E7 | 218 | 129 |

Product Obsolete or Under Obsolescence

XC5200 Series Field Programmable Gate Arrays



| Pin | Description | PC84 | TQ144 | PQ160 | TQ176 | PQ208 | PG223 | BG225 | PQ240 | Boundary Scan Order |
|------|---------------------|------|-------|-------|-------|-------|-------|-------|-------|---------------------|
| 137. | I/O | - | - | - | - | - | R11 | K12 | 137 | 708 |
| 138. | I/O | - | 82 | 92 | 100 | 120 | U13 | K13 | 138 | 711 |
| 139. | I/O | - | 83 | 93 | 101 | 121 | V13 | K14 | 139 | 714 |
| | VCC | - | - | - | - | - | - | VCC* | 140 | - |
| 140. | I/O (D5) | 59 | 84 | 94 | 102 | 122 | U12 | K15 | 141 | 720 |
| 141. | I/O (CS0) | 60 | 85 | 95 | 103 | 123 | V12 | J12 | 142 | 723 |
| 142. | I/O | - | - | - | 104 | 124 | T11 | J13 | 144 | 726 |
| 143. | I/O | - | - | - | 105 | 125 | U11 | J14 | 145 | 732 |
| 144. | I/O | - | 86 | 96 | 106 | 126 | V11 | J15 | 146 | 735 |
| 145. | I/O | - | 87 | 97 | 107 | 127 | V10 | J11 | 147 | 738 |
| 146. | I/O (D4) | 61 | 88 | 98 | 108 | 128 | U10 | H13 | 148 | 744 |
| 147. | I/O | 62 | 89 | 99 | 109 | 129 | T10 | H14 | 149 | 747 |
| | VCC | 63 | 90 | 100 | 110 | 130 | R10 | VCC* | 150 | - |
| | GND | 64 | 91 | 101 | 111 | 131 | R9 | GND* | 151 | - |
| 148. | I/O (D3) | 65 | 92 | 102 | 112 | 132 | T9 | H12 | 152 | 756 |
| 149. | I/O (RS) | 66 | 93 | 103 | 113 | 133 | U9 | H11 | 153 | 759 |
| 150. | I/O | - | 94 | 104 | 114 | 134 | V9 | G14 | 154 | 768 |
| 151. | I/O | - | 95 | 105 | 115 | 135 | V8 | G15 | 155 | 771 |
| 152. | I/O | - | - | - | 116 | 136 | U8 | G13 | 156 | 780 |
| 153. | I/O | - | - | - | 117 | 137 | T8 | G12 | 157 | 783 |
| 154. | I/O (D2) | 67 | 96 | 106 | 118 | 138 | V7 | G11 | 159 | 786 |
| 155. | I/O | 68 | 97 | 107 | 119 | 139 | U7 | F15 | 160 | 792 |
| | VCC | - | - | - | - | - | - | VCC* | 161 | - |
| 156. | I/O | - | 98 | 108 | 120 | 140 | V6 | F14 | 162 | 795 |
| 157. | I/O | - | 99 | 109 | 121 | 141 | U6 | F13 | 163 | 798 |
| 158. | I/O | - | - | - | - | - | R8 | G10 | 164 | 804 |
| 159. | I/O | - | - | - | - | - | R7 | E15 | 165 | 807 |
| | GND | - | 100 | 110 | 122 | 142 | T7 | GND* | 166 | - |
| 160. | I/O | - | - | - | - | - | R6 | E14 | 167 | 810 |
| 161. | I/O | - | - | - | - | - | R5 | F12 | 168 | 816 |
| 162. | I/O | - | - | - | - | 143 | V5 | E13 | 169 | 819 |
| 163. | I/O | - | - | - | - | 144 | V4 | D15 | 170 | 822 |
| 164. | I/O | - | - | 111 | 123 | 145 | U5 | F11 | 171 | 828 |
| 165. | I/O | - | - | 112 | 124 | 146 | T6 | D14 | 172 | 831 |
| 166. | I/O (D1) | 69 | 101 | 113 | 125 | 147 | V3 | E12 | 173 | 834 |
| 167. | I/O (RCLK-BUSY/RDY) | 70 | 102 | 114 | 126 | 148 | V2 | C15 | 174 | 840 |
| 168. | I/O | - | 103 | 115 | 127 | 149 | U4 | D13 | 175 | 843 |
| 169. | I/O | - | 104 | 116 | 128 | 150 | T5 | C14 | 176 | 846 |
| 170. | I/O (D0, DIN) | 71 | 105 | 117 | 129 | 151 | U3 | F10 | 177 | 855 |
| 171. | I/O (DOUT) | 72 | 106 | 118 | 130 | 152 | T4 | B15 | 178 | 858 |
| | CCLK | 73 | 107 | 119 | 131 | 153 | V1 | C13 | 179 | - |
| | VCC | 74 | 108 | 120 | 132 | 154 | R4 | VCC* | 180 | - |
| 172. | I/O (TDO) | 75 | 109 | 121 | 133 | 159 | U2 | A15 | 181 | - |
| | GND | 76 | 110 | 122 | 134 | 160 | R3 | GND* | 182 | - |
| 173. | I/O (A0, WS) | 77 | 111 | 123 | 135 | 161 | T3 | A14 | 183 | 9 |
| 174. | GCK4 (A1, I/O) | 78 | 112 | 124 | 136 | 162 | U1 | B13 | 184 | 15 |
| 175. | I/O | - | 113 | 125 | 137 | 163 | P3 | E11 | 185 | 18 |
| 176. | I/O | - | 114 | 126 | 138 | 164 | R2 | C12 | 186 | 21 |
| 177. | I/O (CS1, A2) | 79 | 115 | 127 | 139 | 165 | T2 | A13 | 187 | 27 |
| 178. | I/O (A3) | 80 | 116 | 128 | 140 | 166 | N3 | B12 | 188 | 30 |
| 179. | I/O | - | - | - | - | - | P4 | F9 | 189 | 33 |

Product Obsolete or Under Obsolescence

XC5200 Series Field Programmable Gate Arrays



| Pin | Description | PQ160 | HQ208 | HQ240 | PG299 | BG225 | BG352 | Boundary Scan Order |
|-----|-----------------|-------|-------|-------|-------|-------|-------|---------------------|
| 8. | I/O (A11) | 148 | 191 | 221 | J3 | B6 | B16 | 165 |
| 9. | I/O | - | - | - | H2 | - | C17 | 171 |
| 10. | I/O | - | - | - | G1 | - | B18 | 174 |
| | VCC | - | - | 222 | E1 | VCC* | VCC* | - |
| 11. | I/O | - | - | 223 | H3 | C6 | C18 | 177 |
| 12. | I/O | - | - | 224 | G2 | F7 | D17 | 183 |
| 13. | I/O | 149 | 192 | 225 | H4 | A5 | A20 | 186 |
| 14. | I/O | 150 | 193 | 226 | F2 | B5 | B19 | 189 |
| | GND | 151 | 194 | 227 | F1 | GND* | GND* | - |
| 15. | I/O | - | - | - | H5 | - | C19 | 195 |
| 16. | I/O | - | - | - | G3 | - | D18 | 198 |
| 17. | I/O | - | 195 | 228 | D1 | D6 | A21 | 201 |
| 18. | I/O | - | 196 | 229 | G4 | C5 | B20 | 207 |
| 19. | I/O | 152 | 197 | 230 | E2 | A4 | C20 | 210 |
| 20. | I/O | 153 | 198 | 231 | F3 | E6 | B21 | 213 |
| 21. | I/O (A12) | 154 | 199 | 232 | G5 | B4 | B22 | 219 |
| 22. | I/O (A13) | 155 | 200 | 233 | C1 | D5 | C21 | 222 |
| 23. | I/O | - | - | - | F4 | - | D20 | 225 |
| 24. | I/O | - | - | - | E3 | - | A23 | 234 |
| 25. | I/O | - | - | 234 | D2 | A3 | D21 | 237 |
| 26. | I/O | - | - | 235 | C2 | C4 | C22 | 243 |
| 27. | I/O | 156 | 201 | 236 | F5 | B3 | B24 | 246 |
| 28. | I/O | 157 | 202 | 237 | E4 | F6 | C23 | 249 |
| 29. | I/O (A14) | 158 | 203 | 238 | D3 | A2 | D22 | 258 |
| 30. | I/O (A15) | 159 | 204 | 239 | C3 | C3 | C24 | 261 |
| | VCC | 160 | 205 | 240 | A2 | VCC* | VCC* | - |
| | GND | 1 | 2 | 1 | B1 | GND* | GND* | - |
| 31. | GCK1 (A16, I/O) | 2 | 4 | 2 | D4 | D4 | D23 | 270 |
| 32. | I/O (A17) | 3 | 5 | 3 | B2 | B1 | C25 | 273 |
| 33. | I/O | 4 | 6 | 4 | B3 | C2 | D24 | 279 |
| 34. | I/O | 5 | 7 | 5 | E6 | E5 | E23 | 282 |
| 35. | I/O (TDI) | 6 | 8 | 6 | D5 | D3 | C26 | 285 |
| 36. | I/O (TCK) | 7 | 9 | 7 | C4 | C1 | E24 | 294 |
| 37. | I/O | - | - | - | A3 | - | F24 | 297 |
| 38. | I/O | - | - | - | D6 | - | E25 | 303 |
| 39. | I/O | 8 | 10 | 8 | E7 | D2 | D26 | 306 |
| 40. | I/O | 9 | 11 | 9 | B4 | G6 | G24 | 309 |
| 41. | I/O | - | 12 | 10 | C5 | E4 | F25 | 315 |
| 42. | I/O | - | 13 | 11 | A4 | D1 | F26 | 318 |
| 43. | I/O | - | - | 12 | D7 | E3 | H23 | 321 |
| 44. | I/O | - | - | 13 | C6 | E2 | H24 | 327 |
| 45. | I/O | - | - | - | E8 | - | G25 | 330 |
| 46. | I/O | - | - | - | B5 | - | G26 | 333 |
| | GND | 10 | 14 | 14 | A5 | GND* | GND* | - |
| 47. | I/O | 11 | 15 | 15 | B6 | F5 | J23 | 339 |
| 48. | I/O | 12 | 16 | 16 | D8 | E1 | J24 | 342 |
| 49. | I/O (TMS) | 13 | 17 | 17 | C7 | F4 | H25 | 345 |
| 50. | I/O | 14 | 18 | 18 | B7 | F3 | K23 | 351 |
| | VCC | - | - | 19 | A6 | VCC* | VCC* | - |
| 51. | I/O | - | - | 20 | C8 | F2 | L24 | 354 |
| 52. | I/O | - | - | 21 | E9 | F1 | K25 | 357 |
| 53. | I/O | - | - | - | B8 | - | L25 | 363 |

Product Obsolete or Under Obsolescence

XC5200 Series Field Programmable Gate Arrays



| Pin | Description | PQ160 | HQ208 | HQ240 | PG299 | BG225 | BG352 | Boundary Scan Order |
|------|---------------------|-------|-------|-------|-------|-------|-------|---------------------|
| 190. | I/O | - | - | - | X8 | - | M4 | 951 |
| 191. | I/O | - | - | - | V9 | - | L1 | 954 |
| 192. | I/O (D2) | 106 | 138 | 159 | W8 | G11 | J1 | 960 |
| 193. | I/O | 107 | 139 | 160 | X7 | F15 | K3 | 963 |
| | VCC | - | - | 161 | X5 | VCC* | VCC* | |
| 194. | I/O | 108 | 140 | 162 | V8 | F14 | J2 | 966 |
| 195. | I/O | 109 | 141 | 163 | W7 | F13 | J3 | 972 |
| 196. | I/O | - | - | 164 | U8 | G10 | K4 | 975 |
| 197. | I/O | - | - | 165 | W6 | E15 | G1 | 978 |
| | GND | 110 | 142 | 166 | X6 | GND* | GND* | |
| 198. | I/O | - | - | - | T8 | - | H2 | 984 |
| 199. | I/O | - | - | - | V7 | - | H3 | 987 |
| 200. | I/O | - | - | 167 | X4 | E14 | J4 | 990 |
| 201. | I/O | - | - | 168 | U7 | F12 | F1 | 996 |
| 202. | I/O | - | 143 | 169 | W5 | E13 | G2 | 999 |
| 203. | I/O | - | 144 | 170 | V6 | D15 | G3 | 1002 |
| 204. | I/O | 111 | 145 | 171 | T7 | F11 | F2 | 1008 |
| 205. | I/O | 112 | 146 | 172 | X3 | D14 | E2 | 1011 |
| 206. | I/O (D1) | 113 | 147 | 173 | U6 | E12 | F3 | 1014 |
| 207. | I/O (RCLK-BUSY/RDY) | 114 | 148 | 174 | V5 | C15 | G4 | 1020 |
| 208. | I/O | - | - | - | W4 | - | D2 | 1023 |
| 209. | I/O | - | - | - | W3 | - | F4 | 1032 |
| 210. | I/O | 115 | 149 | 175 | T6 | D13 | E3 | 1035 |
| 211. | I/O | 116 | 150 | 176 | U5 | C14 | C2 | 1038 |
| 212. | I/O (D0, DIN) | 117 | 151 | 177 | V4 | F10 | D3 | 1044 |
| 213. | I/O (DOUT) | 118 | 152 | 178 | X1 | B15 | E4 | 1047 |
| | CCLK | 119 | 153 | 179 | V3 | C13 | C3 | - |
| | VCC | 120 | 154 | 180 | W1 | VCC* | VCC* | - |
| 214. | I/O (TDO) | 121 | 159 | 181 | U4 | A15 | D4 | 0 |
| | GND | 122 | 160 | 182 | X2 | GND* | GND* | - |
| 215. | I/O (A0, WS) | 123 | 161 | 183 | W2 | A14 | B3 | 9 |
| 216. | GCK4 (A1, I/O) | 124 | 162 | 184 | V2 | B13 | C4 | 15 |
| 217. | I/O | 125 | 163 | 185 | R5 | E11 | D5 | 18 |
| 218. | I/O | 126 | 164 | 186 | T4 | C12 | A3 | 21 |
| 219. | I/O (A2, CS1) | 127 | 165 | 187 | U3 | A13 | D6 | 27 |
| 220. | I/O (A3) | 128 | 166 | 188 | V1 | B12 | C6 | 30 |
| 221. | I/O | - | - | - | R4 | - | B5 | 33 |
| 222. | I/O | - | - | - | P5 | - | A4 | 39 |
| 223. | I/O | - | - | 189 | U2 | F9 | C7 | 42 |
| 224. | I/O | - | - | 190 | T3 | D11 | B6 | 45 |
| 225. | I/O | 129 | 167 | 191 | U1 | A12 | A6 | 51 |
| 226. | I/O | 130 | 168 | 192 | P4 | C11 | D8 | 54 |
| 227. | I/O | - | 169 | 193 | R3 | B11 | B7 | 57 |
| 228. | I/O | - | 170 | 194 | N5 | E10 | A7 | 63 |
| 229. | I/O | - | - | 195 | T2 | - | D9 | 66 |
| 230. | I/O | - | - | - | R2 | - | C9 | 69 |
| | GND | 131 | 171 | 196 | T1 | GND* | GND* | - |
| 231. | I/O | 132 | 172 | 197 | N4 | A11 | B8 | 75 |
| 232. | I/O | 133 | 173 | 198 | P3 | D10 | D10 | 78 |
| 233. | I/O | - | - | 199 | P2 | C10 | C10 | 81 |
| 234. | I/O | - | - | 200 | N3 | B10 | B9 | 87 |
| | VCC | - | - | 201 | R1 | VCC* | VCC* | - |

Product Obsolete or Under Obsolescence



XC5200 Series Field Programmable Gate Arrays

Revisions

| Version | Description |
|---------|---|
| 12/97 | Rev 5.0 added -3, -4 specification |
| 7/98 | Rev 5.1 added Spartan family to comparison, removed HQ304 |
| 11/98 | Rev 5.2 All specifications made final. |